

Notice of References Cited	Application/Control No. 10/563,274		Applicant(s)/Patent Under Reexamination SHIONO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0058028	03-2005	Aoyama et al.	369/013.35
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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